

# ITC-Asia 2018 Best Paper Award

International Test Conference in Asia (ITC-Asia) was established in 2017 to stimulate discussions and interactions in LSI test technology between the academia and the industry around the globe, with a focus in Asia. Its 2nd event (ITC-Asia 2018), was held in Harbin, China, from August 15 to 17, 2018. From 52 papers submitted from 10 countries and regions, 24 papers from 9 countries and regions were accepted based on stringent reviews by Program Committee members and external reviewers. To encourage innovative and high-impact research work, the ITC-Asia 2018 Organizing Committee decided to present a Best Paper Award. The selection was conducted by the ITC-Asia 2018 Best Paper Selection Committee, comprising of 5 members selected from the ITC-Asia 2018 Program Committee.

Here I am privileged to announce the winner of the ITC-Asia 2018 Best Paper Award:

## **Leveraging DRAM Refresh to Protect the Memory Timing Channel of Cloud Chip Multi-Processors**

**Ying Wang, Wen Li, Huawei Li, Xiaowei Li**

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University of Chinese Academy of Sciences, Beijing, China*

On behalf of the Program Committee and the Best Paper Selection Committee of ITC-Asia 2018, I congratulate the authors of the ITC-Asia 2018 Best Paper for their excellent research achievement and outstanding contribution to ITC-Asia 2018. I also thank all ITC-Asia 2018 Best Paper Selection Committee members for their time and efforts in the process of ITC-Asia 2018 Best Paper selection.

Xiaoqing Wen  
*Kyushu Institute of Technology*

ITC-Asia 2018 Best Paper Selection Committee Chair  
& ITC-Asia 2018 Program Committee Co-Chair